

**Notice of References Cited**

Application/Control No.

10/530,730

Applicant(s)/Patent Under  
Reexamination  
SHIOYA ET AL.

Examiner

Duy-Vu N. Deo

Art Unit

1765

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0042889	02-2005	Lee et al.	438/780
*	B	US-6,656,837	12-2003	Xu et al.	438/676
*	C	US-6,303,523	10-2001	Cheung et al.	438/780
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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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